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```
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((foreground or object)
<sentence> (average or mean or
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expectation))and correlat*
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Example: acoustic imaging (means acoustic and imaging)
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Example: optical <and> (fiber <or> fibre) <in> ti
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```
(object <near/6> recogni*)
and (pattern <near/4> match*)
and ( (foreground and
background) <paragraph>
```


Note: This function returns plural and suffixed forms of the keyword(s).

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